



Expertise Applied | Answers Delivered

8755 W. Higgins Road
Suite 500
Chicago, IL 60631

www.littelfuse.com

Apr 9th, 2026

Re: LFPCN41569 - Littelfuse TVS AUTO TP6KE&TP1.5KE Additional Assembly&Testing Site Approval

To Our Valued Customers,

In order to support fast-growing demand and secure continuity of supply for our customers, Littelfuse will approve additional assembly & testing site in China for DO-15&DO-201 Package, TP6KE and TP1.5KE AUTO TVS.

There will be no change to the form, fit, function, quality, or reliability of the products.

All affected products have been fully qualified in accordance with established performance and reliability criteria. Please refer to the attached affected parts list and the attached documentation for qualification result and change details.

Form, fit, function changes: None

Part number changes: None

Effective date: Jan 4, 2027

Replacement products: N/A

Last time buy: N/A

This notification is for your information and acknowledgement. If you have any other questions or concerns, please contact your local sales team or product team below for further assistance.

We value your business and look forward to assisting you whenever possible.

Best Regards,

Victoria You
Assistant Product Manager
Automotive TVS
Tel: +86 510 85277701 ext. 7710
VYou@Littelfuse.com



PCN Report

Prepared By : Tianhua Wang-Product Engineer,
 Ada Du-Sr. OSAT Engineer,
Date : 1/30/2026
Device : DO-15&DO-201 Package Product
Revision : 2

1.0 Objective:

The purpose of this project is to qualify an additional assembly& testing location for DO-15&DO-201 Package Product.
 Succeeding pages summarize the physical, electrical and reliability test performed in qualification lots.

2.0 Applicable Devices:

Package	Part Numbers
DO-15	TP6KE Series/P6KE510CA-SU
DO-201	TP1.5KE Series

3.0 Assembly, Process & Material Differences/Changes:

3.1 Assembly and Process Changes

There's no change in the process flow.

3.2 Material Changes

TP6KE:

Material	1 st Source		2 nd Source		Changed?
	Material Name	Supplier	Material Name	Supplier	
Die	Silicon Wafer	Littelfuse	Silicon Wafer	Littelfuse	No
Lead	0.78mm Copper+1‰Ag	Supper	0.72mm Copper	MEILIN	Yes
Solder Wafer	Pb92.5 Sn5 Ag2.5	PFARR	Pb92.5 Sn5 Ag2.5	Bondron	Yes
Molding Compound	EME-G720C	Sumitomo	EME-G720C E115 TYPED6	Sumitomo Sumikon	Yes

TP1.5KE:

Material	1 st Source		2 nd Source		Changed?
	Material Name	Supplier	Material Name	Supplier	

Die	Silicon Wafer	Littelfuse	Silicon Wafer	Littelfuse	No
Lead	1.015mm Bare copper	Supper	1.015mm Bare copper	MEILIN	Yes
Solder Wafer	Pb92.5 Sn5 Ag2.5	PFARR	Pb92.5 Sn5 Ag2.5	Bondron	Yes
Molding Compound	EME-G720C	Sumitomo	EME-G720C	Sumitomo	No

4.0 Packing Method

4.1 Packing Material

Packing	1 st Source	2 nd Source
Tape & Reel	Gray cardboard reel, 13 inches Details dimension refer to 4.2/4.3	Gray cardboard reel, 13 inches Details dimension refer to 4.2/4.3
Label	Size: 102mmx76mm Details dimension refer to 4.5	Size: 102mmx76mm Details dimension refer to 4.5

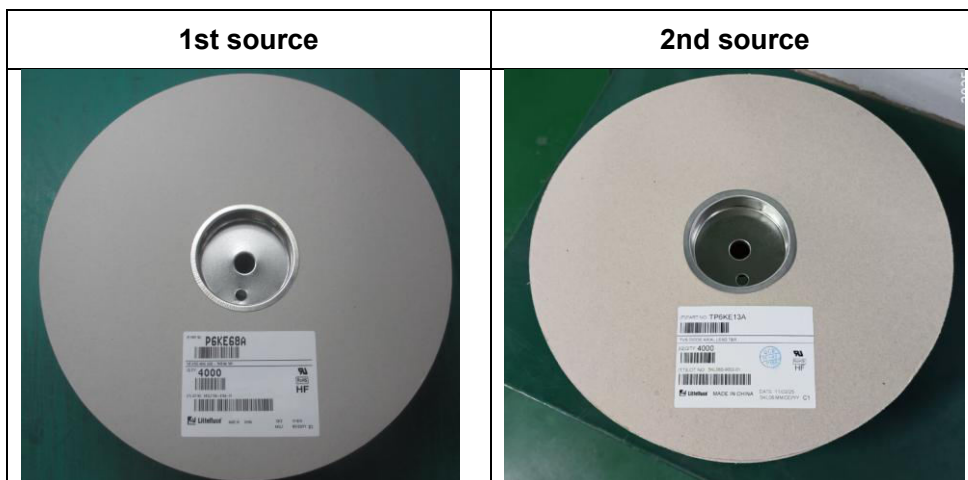
4.2 Tape Dimension

Tape Dimension no change

4.3 Reel Dimension

Reel Dimension no change

Reel



4.5 Label

1st source	2nd source
<p>(P)PART NO: TP1.5KE12CA  TVS DIODE AXIAL LEAD - TP1.5KE12CA T&R</p> <p>(Q)QTY: 150  (1T)LOT NO: 5G6DKC-2401-02 </p> <p>QCG 2025.07.29 ACC</p> <p>RoHS HF</p> <p>DATE 07/17/25 C1 Littelfuse MADE IN CHINA 5G6DK MM/DD/YY</p>	<p>(P)PART NO: TP1.5KE12A  TVS DIODE AXIAL LEAD - TP1.5KE12A T&R</p> <p>(Q)QTY: 1200  (1T)LOT NO: 5KL06B-9002-02 </p> <p>QCG 2025.11.02 PASS</p> <p>RoHS HF</p> <p>DATE 11/02/25 Littelfuse MADE IN CHINA 5KL06 MM/DD/YY C1</p>

5.0 Physical Differences/Changes:

POD no change.

6.0 Reliability Test Results Summary:

TP6KE



Discrete Semiconductor Component Qualification Result

General Specification:	AEC-Q101 Rev E	Report Date:	October 23, 2025
Supplier:	Littelfuse Semiconductor (Wuxi) Co., Ltd.	Supplier Manufacturing Site:	Zibo, China
User Generic P/N:	TP6KE13A-TP6KE91A	Package Type:	DO-15
Supplier Internal P/N:	TP6KE13A-TP6KE91A	Product Type:	Automotive TVS
		Laboratory Name:	Wuxi Technical Center
		Qualification Reporter:	Tianhua Wang, Product Engineer

Test #	Test Description	Test Conditions	Standard/Method	Littelfuse Test Ref#	# Lots	# Sample per lot	# Tested	# Failed	Remarks
1	Pre & Post Stress Parameter Test	Electrical parameter test (I_R & V_{RR}) at 25°C	Datasheet spec	All	All	All	All	0	Test before and after all test
2	Pre-conditioning	24hrs 125°C bake, 168hrs 85°C & 85%RH temperature humidity, 3 times reflow of peak temperature 260°C	JESD22-A-113	NA	NA	NA	NA	NA	No need for leaded parts
3	External Visual	Inspect part construction, marking and workmanship. Pass by OQC inspection in assembly house.	JESD22-B-101	All	All	All	All	0	
4	Parametric Verification	Electrical parameter test at different Temp.	Individual AEC user specification	TR24-09-011495 TR25-03-015063 TR24-09-011510	3	25	75	0	
5	High Temperature Reverse Bias	$T_A = T_J$, 1008hrs, DC biased at V_R	MIL-STD-750-1 M1038 Method A	TR24-09-011495 TR25-03-015063 TR24-09-011510	3	77	231	0	
5a	AC Blocking Voltage	Not applicable, for Thyristors only	MIL-STD-750-1 M1040 condition A	NA	NA	NA	NA	NA	
5b	Steady State Operational	Not applicable, for Voltage Regulators	MIL-STD-750-1 M1038 condition B	NA	NA	NA	NA	NA	
6	High Temperature Gate Bias	Not applicable, for MOS & IGBT parts only	JESD22-A-108	NA	NA	NA	NA	NA	
7	Temperature Cycling	T_A : -55°C to 150°C, 1000 cycles	JESD22-A-104	TR24-09-011495 TR25-03-015063 TR24-09-011510	3	77	231	0	
7a	Temperature Cycling Hot Test	Not applicable, for MOSFET parts	JESD22-A-104	NA	NA	NA	NA	NA	
7a alt	TC Delamination Test	Not applicable, for MOSFET parts	JESD22-A-104 J-STD-035	NA	NA	NA	NA	NA	
8	Unbiased Highly Accelerated Stress Test	96 hours at $T_A = 130^\circ\text{C}$ & 85%RH	JESD22-A-118	TR24-09-011495 TR25-03-015063 TR24-09-011510	3	77	231	0	
8 alt	Autoclave	96 hours at $T_A = 121^\circ\text{C}$ & 100%RH, 2 atm	JESD22-A-102	NA	NA	NA	NA	NA	UHAST as replace
9	High Humidity High Temp Reverse Bias	$T_A = 85^\circ\text{C}$, 85%RH, 1008hours, DC biased at V_R not exceed 100V	JESD22-A-101	TR24-09-011495 TR25-03-015063 TR24-09-011510	3	77	231	0	
9 alt	Highly Accelerated Stress Test	96 hours at $T_A = 130^\circ\text{C}$ & 85%RH, biased at 80% rated voltage, not exceed 42V	JESD22-A-110	NA	NA	NA	NA	NA	Already test HSTRB, can cover HAST
10	Intermittent Operational Life	$T_A = 25^\circ\text{C}$, $\Delta T_J >= 100^\circ\text{C}$, TON/OFF = 2 minutes, 15000cycles	MIL-STD-750 Method 1037	NA	NA	NA	NA	NA	
10 alt	Power Temperature Cycling	Not required for TVS parts	JESD22-A-105	NA	NA	NA	NA	NA	
11	High Temperature Storage Life	$T_A = T_{STB}$, 1008hours	JESD22-A-103	NA	NA	NA	NA	NA	
12	ESD HBM Characterization	16KV HBM discharge, met Class 3B requirement	AEC Q101-001	TR24-09-011495 TR25-03-015063 TR24-09-011510	3	30	90	0	
13	ESD CDM Characterization	2KV CDM discharge, met Class 3B requirement	AEC Q101-005	NA	NA	NA	NA	NA	
14	ESD IEC Characterization	30KV IEC61000-4-2 contact discharge	IEC61000-4-2	NA	NA	NA	NA	NA	
15	Destructive Physical Analysis	Destructive Physical Analysis, no obvious defect	AEC Q101-004 Section 4	TR24-11-012730 TR24-11-012731	1	2	2	0	Random samples from passed HSTRB and TC
16	Physical Dimension	Per package dimension specification Pass by OQC inspection in assembly house	JESD22-B-100	NA	1	30	30	0	
17	Terminal Strength	Evaluate lead integrity of through-hole leaded part only.	MIL-STD-750-2 Method 2036	NA	1	30	30	0	
18	Resistance to Solvents	Verify marking permanency	JESD22-B-107	NA	1	30	30	0	
19	Constant Acceleration	Not applicable, required for hermetic package parts only	MIL-STD-750 Method 2006	NA	NA	NA	NA	NA	
20	Vibration Variable Frequency	Not applicable, required for hermetic package parts only	JESD22-B-103	NA	NA	NA	NA	NA	
21	Mechanical Shock	Not applicable, required for hermetic package parts only	JESD22-B-104	NA	NA	NA	NA	NA	
22	Hermeticity	Not applicable, required for hermetic package parts only	JESD22-A-109	NA	NA	NA	NA	NA	
23	Resistance to Solder Heat	260°C, 10secs	JESD22-A-111	TR24-09-011495 TR25-03-015063 TR24-09-011510	3	30	90	0	
24	Solderability	245°C ± 5°C, 5 ± 0.5s	J-STD-002	TR24-09-011495 TR25-03-015063 TR24-09-011510	3	10	30	0	
25	Thermal Resistance	Typical Thermal Resistance Junction to Lead Per datasheet spec	JESD-24-3, 24-4, 24-6 as appropriate	TR24-09-011497	1	10	10	0	Only test for uni-directional product
26	Wire Bond Strength	Not applicable, only required for wire bond	MIL-STD-750 Method 2037	NA	NA	NA	NA	NA	
27	Bond Shear	Not applicable, only required for wire bond	JESD22-B116	NA	NA	NA	NA	NA	
28	Die Shear	Not applicable, only required for wire bond	MIL-STD-750 Method 2017	NA	NA	NA	NA	NA	
29	Unclamped Inductive Switching	Not applicable, only required for power MOS & IGBT	AEC-Q101-004 Section 2	NA	NA	NA	NA	NA	
30	Dielectric Integrity	Not applicable, only required for power MOS & IGBT	AEC-Q101-004 Section 3	NA	NA	NA	NA	NA	
31	Short Circuit Reliability Characterization	Not applicable, only required for smart power parts	AEC-Q101-006	NA	NA	NA	NA	NA	
32	Lead Free	Per AEC-Q101	AEC-Q005	NA	1	9	9	0	
33	V_f Test	V_f @ differenet IF, 25°C	Datasheet spec	TR24-09-011497 TR24-09-011511	2	10	20	0	Only test for uni-direction production
34	Capacitance	Bias voltage = 1V, 2V, 5V, 10V, 50% V_R , 100% V_R , 1MHz, $T_J = 25^\circ\text{C}$	Individual AEC user specification	TR24-09-011497 TR25-03-015123 TR24-09-011511	3	10	30	0	
35	10x1000us Surge Life	10x1000us waveform, 25°C, 30hits	Individual AEC user specification	TR24-09-011497 TR25-03-015123 TR24-09-011511	3	10	30	0	
36	10x1000us Surge Out	10x1000us waveform, 25°C	Individual AEC user specification	TR24-09-011497 TR25-03-015123 TR24-09-011511	3	10	30	0	

Conclusion:	All samples passed all requested test items by AEC-Q101 Rev.E successfully.
Footnotes 1:	Tests are conducted without a bias condition unless otherwise stated.
Footnotes 2:	Reliability data from product tests that is representative of similar products having structural similarity, commonality of production processes and product technology will be generically applied to those products.
Footnotes 3:	Tests are conducted on TP6KE13A, TP6KE56CA, TP6KE91A



TP1.5KE

Discrete Semiconductor Component Qualification Result									
General Specification:		AEC-Q101 Rev E			Report Date:		October 23, 2025		
Supplier:		Littelfuse Semiconductor (Wuxi) Co., Ltd.			Supplier Manufacturing Site:		Zibo, China		
User Generic P/N:		TP1.5KE12A-TP1.5KE47A			Package Type:		DO-201		
Supplier Internal P/N:		TP1.5KE12A-TP1.5KE47A			Product Type:		Automotive TVS		
					Laboratory Name:		Wuxi Technical Center		
					Qualification Reporter:		Tianhua Wang, Product Engineer		
Test #	Test Description	Test Conditions	Standard/Method	Littelfuse Test Ref#	# Lots	# Sample per lot	# Tested	# Failed	Remarks
1	Pre & Post Stress Parameter Test	Electrical parameter test (I_R & V_{RRM}) at 25°C	Datasheet spec	All	All	All	All	0	Test before and after all test
2	Pre-conditioning	24hrs 125°C bake, 168hrs 85°C & 85%RH temperature humidity, 3 times reflow of peak temperature 260°C	JESD22-A-113	NA	NA	NA	NA	NA	No need for leaded parts
3	External Visual	Inspect part construction, marking and workmanship. Pass by OQC inspection in assembly house.	JESD22-B-101	All	All	All	All	0	
4	Parametric Verification	Electrical parameter test at different Temp.	Individual AEC user specification	TR25-03-014967 TR25-03-015087	3	25	75	0	
5	High Temperature Reverse Bias	$T_A = T_J$, 1008hrs, DC biased at V_R	MIL-STD-750-1 M1038 Method A	TR25-03-014967 TR25-03-015087	3	77	231	0	
5a	AC Blocking Voltage	Not applicable, for Thyristors only	MIL-STD-750-1 M1040 condition A	NA	NA	NA	NA	NA	
5b	Steady State Operational	Not applicable, for Voltage Regulators	MIL-STD-750-1 M1038 condition B	NA	NA	NA	NA	NA	
6	High Temperature Gate Bias	Not applicable, for MOS & IGBT parts only	JESD22-A-108	NA	NA	NA	NA	NA	
7	Temperature Cycling	T_A : -55°C to 150°C, 1000 cycles	JESD22-A-104	TR25-03-014967 TR25-03-015087	3	77	231	0	
7a	Temperature Cycling Hot Test	Not applicable, for MOSFET parts	JESD22-A-104	NA	NA	NA	NA	NA	
7a alt	TC Delamination Test	Not applicable, for MOSFET parts	JESD22-A-104 J-STD-035	NA	NA	NA	NA	NA	
8	Unbiased Highly Accelerated Stress Test	96 hours at $T_A=130°C$ & 85%RH	JESD22-A-118	TR25-03-014967 TR25-03-015087	3	77	231	0	
8 alt	Autoclave	96 hours at $T_A = 121°C$ & 100%RH, 2 atm	JESD22-A-102	NA	NA	NA	NA	NA	UHAST as replace
9	High Humidity High Temp Reverse Bias	$T_A = 85°C$, 85%RH, 1008hrs, DC biased at V_R not exceed 100V	JESD22-A-101	TR25-03-014967 TR25-03-015087	3	77	231	0	
9 alt	Highly Accelerated Stress Test	96 hours at $T_A = 130°C$ & 85%RH, biased at 80% rated voltage, not exceed 42V	JESD22-A-110	NA	NA	NA	NA	NA	Already test H3TRB, can cover HAST
10	Intermittent Operational Life	$T_A = 25°C$, $\Delta T_J \geq 100°C$, TON/OFF = 2 minutes, 15000cycles	MIL-STD-750 Method 1037	NA	NA	NA	NA	NA	
10 alt	Power Temperature Cycling	Not required for TVS parts	JESD22-A-105	NA	NA	NA	NA	NA	
11	High Temperature Storage Life	$T_A = T_{STP}$, 1008hours	JESD22-A-103	TR25-03-014967 TR25-03-015087	3	77	231	0	
12	ESD HBM Characterization	16KV HBM discharge, met Class 3B requirement	AEC Q101-001	TR25-03-014967 TR25-03-015087	3	30	90	0	
13	ESD CDM Characterization	2KV CDM discharge, met Class 3B requirement	AEC Q101-005	NA	NA	NA	NA	NA	
14	ESD IEC Characterization	30KV IEC61000-4-2 contact discharge	IEC61000-4-2	NA	NA	NA	NA	NA	
15	Destructive Physical Analysis	Destructive Physical Analysis, no obvious defect	AEC Q101-004 Section 4	TR25-05-016083 TR25-05-016084	1	2	2	0	Random samples from passed H3TRB and TC
16	Physical Dimension	Per package dimension specification Pass by OQC inspection in assembly house	JESD22-B-100	NA	1	30	30	0	
17	Terminal Strength	Evaluate lead integrity of through-hole leaded partsonly.	MIL-STD-750-2 Method 2036	NA	1	30	30	0	
18	Resistance to Solvents	Verify marking permanency	JESD22-B-107	NA	1	30	30	0	
19	Constant Acceleration	Not applicable, required for hermetic packageed parts only	MIL-STD-750 Method 2006	NA	NA	NA	NA	NA	
20	Vibration Variable Frequency	Not applicable, required for hermetic packageed parts only	JESD22-B-103	NA	NA	NA	NA	NA	
21	Mechanical Shock	Not applicable, required for hermetic packageed parts only	JESD22-B-104	NA	NA	NA	NA	NA	
22	Hermeticity	Not applicable, required for hermetic packageed parts only	JESD22-A-109	NA	NA	NA	NA	NA	
23	Resistance to Solder Heat	260°C, 10secs	JESD22-A-111	TR25-03-014967 TR25-03-015087	3	30	90	0	
24	Solderability	245°C ± 5°C, 5 ± 0.5s	J-STD-002	TR25-03-014967 TR25-03-015087	3	10	30	0	
25	Thermal Resistance	Typical Thermal Resistance Junction to Lead Per datasheet spec	JESD-24-3, 24-4, 24-6 as appropriate	TR24-09-011628	1	10	10	0	Only test for uni-directional product
26	Wire Bond Strength	Not applicable, only required for wire bond	MIL-STD-750 Method 2037	NA	NA	NA	NA	NA	
27	Bond Shear	Not applicable, only required for wire bond	JESD22-B116	NA	NA	NA	NA	NA	
28	Die Shear	Not applicable, only required for wire bond	MIL-STD-750 Method 2017	NA	NA	NA	NA	NA	
29	Unclamped Inductive Switching	Not applicable, only required for power MOS & IGBT	AEC-Q101-004 Section 2	NA	NA	NA	NA	NA	
30	Dielectric Integrity	Not applicable, only required for power MOS & IGBT	AEC-Q101-004 Section 3	NA	NA	NA	NA	NA	
31	Short Circuit Reliability Characterization	Not applicable, only required for smart power parts	AEC-Q101-006	NA	NA	NA	NA	NA	
32	Lead Free	Per AEC-Q101	AEC-Q005	NA	1	9	9	0	
33	V_R Test	V_R @ differenet IF, 25°C	Datasheet spec	TR24-09-011628	1	10	10	0	Only test for uni-direction production
34	Capacitance	Bias voltage = 1V, 2V, 5V, 10V, 50% V_R , 100% V_R , 1MHZ, $T_J = 25°C$	Individual AEC user specification	TR25-03-015122 TR25-03-015124 TR24-09-011628	3	10	30	0	
35	10x1000us Surge Life	10x1000us waveform, 25°C, 30hits	Individual AEC user specification	TR25-03-015122 TR25-03-015124 TR24-09-011628	3	10	30	0	
36	10x1000us Surge Out	10x1000us waveform, 25°C	Individual AEC user specification	TR25-03-015122 TR25-03-015124 TR24-09-011628	3	10	30	0	
Conclusion:		All samples passed all requested test items by AEC-Q101 Rev.E successfully.							
Footnotes 1:		Tests are conducted without a bias condition unless otherwise stated.							
Footnotes 2:		Reliability data from product tests that is representative of similar products having structural similarity, commonality of production processes and product technology will be generically applied to those products.							
Footnotes 3:		Tests are conducted on TP1.5KE12CA, TP1.5KE20CA, TP1.5KE47A							



Estimate of Failure Rate, MTBF, FITS for a Given Operation Temperature

Temp °C	% FR/khrs	MTBF (K)	FITS
30	0.000002	60776643	0.02
55	0.00005	1935420	0.52
85	0.00037	269211	3.71
100	0.00216	46264	21.6
125	0.01523	6565	152
150	0.08523	1173	852
175	0.39351	254	3935

4. The **Mean-Time-Between-Failure (MTBF)** in hours and the percent failure rate per 1000 hours (%FR/khr) are computed at a 60% confidence level using the chi square method and the Arrhenius derating model for various junction operating temperatures. For the calculations, a value of 1 eV was used for the activation energy.

7.0 Electrical Characteristic Summary:

There is no change in electrical characteristics. Characterization data is available upon request.

TP6KE

Test Items		Condition	S/S	Results	ETR #
Parametric		V _{BR} , I _R	30	0/30	TR24-09-011497 TR25-03-015123 TR24-09-011511
VF		Datasheet condition	10	0/10	
Surge Out test	10X1000us	1 hit, at 25°C from 1.0IPP, add 0.1 IPP one step, pass 1.2IPP	30	0/30	
Surge Life test	10X1000us	1 hit,30 hits, 1.0IPP	30	0/30	

Detail Surge Test Summary:

Part No.	Package	ETR#	Surge out 10X1000us	Surge Life 10X1000us
TP6KE13A	DO-15	TR24-09-011497	1.5IPP	0/10
TP6KE56CA	DO-15	TR25-03-015123	1.7IPP	0/10
TP6KE91A	DO-15	TR24-09-011511	1.2IPP	0/10

TP1.5KE

Test Items		Condition	S/S	Results	ETR #
Parametric		V _{BR} , I _R	30	0/30	TR25-03-015122 TR25-03-015124 TR24-09-011628
VF		Datasheet condition	20	0/20	
Surge Out test	10X1000us	1 hit, at 25°C from 1.0IPP, add 0.1 IPP one step, pass 1.2IPP	30	0/30	
Surge Life test	10X1000us	1 hit,30 hits, 1.0IPP	30	0/30	

Detail Surge Test Summary:



Part No.	Package	ETR#	Surge out 10X1000us	Surge Life 10X1000us
TP1.5KE12CA	DO-201	TR25-03-015122	1.6IPP	0/10
TP1.5KE20CA	DO-201	TR25-03-015124	1.6IPP	0/10
TP1.5KE47A	DO-201	TR24-09-011628	1.3IPP	0/10

8.0 Changed Part Identification:

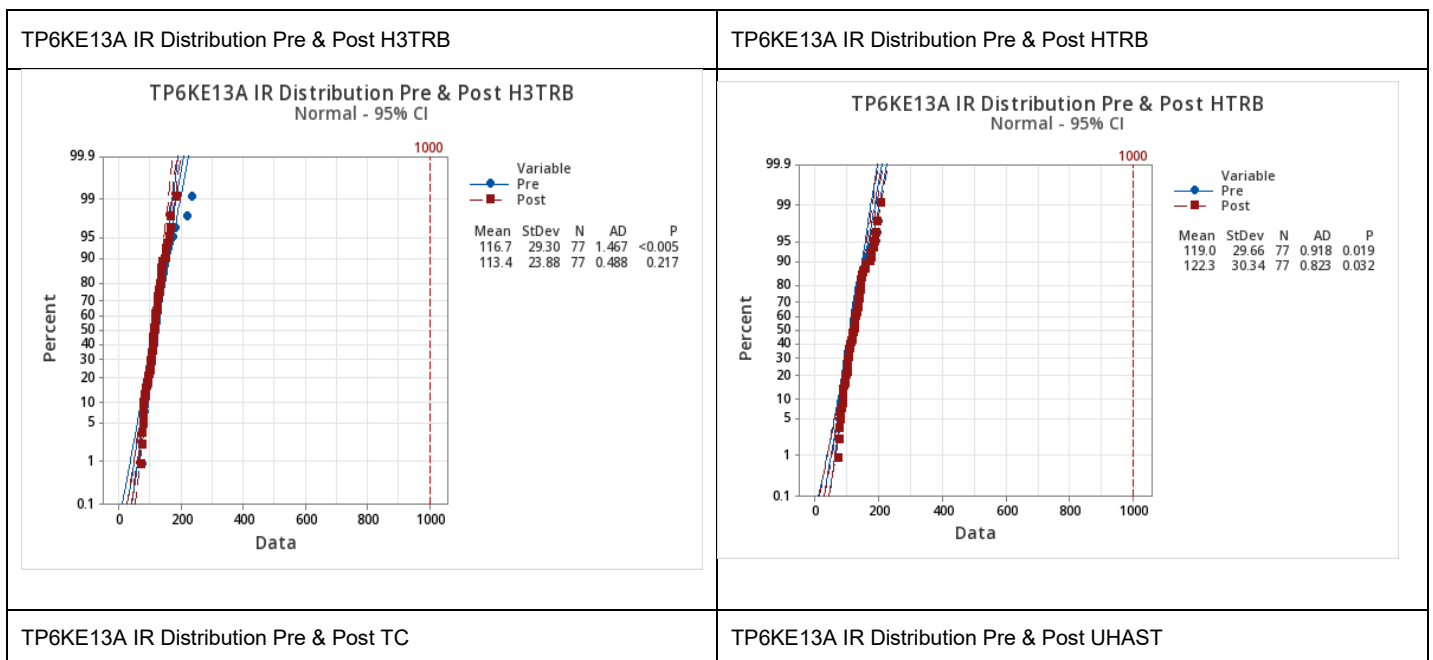
There is no Part used in affected products.

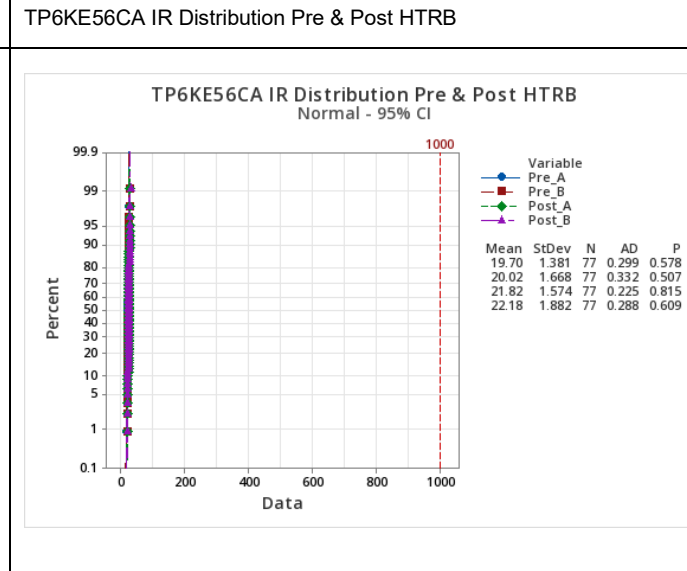
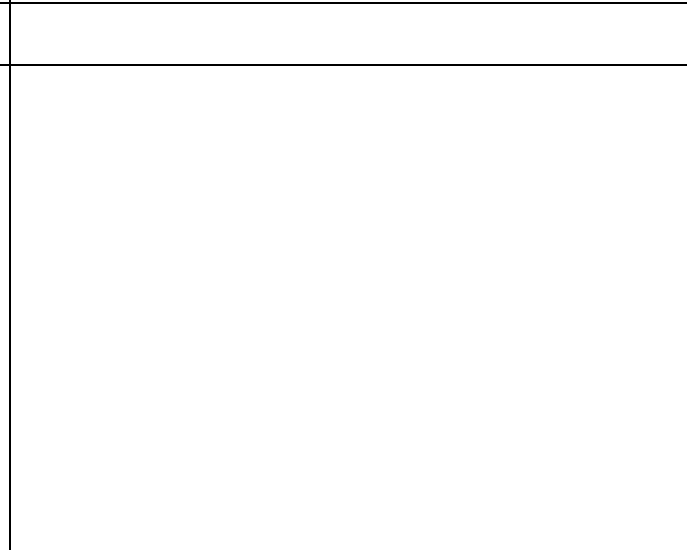
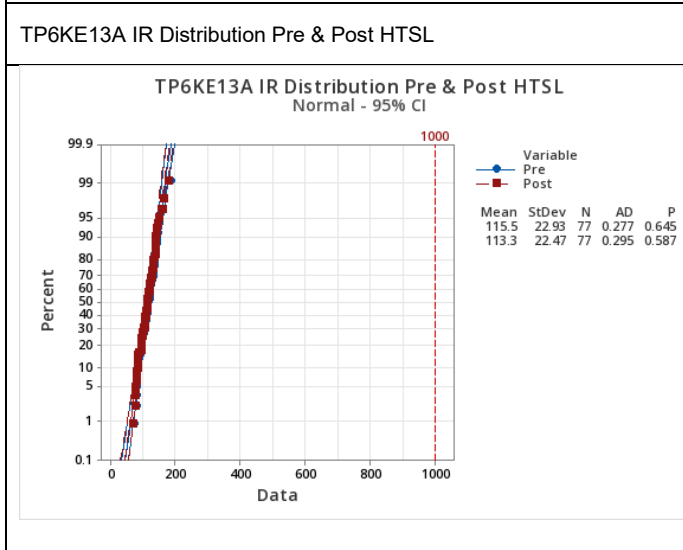
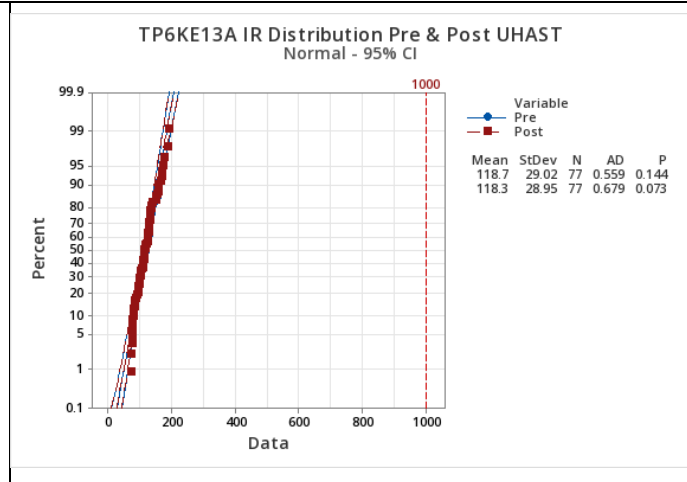
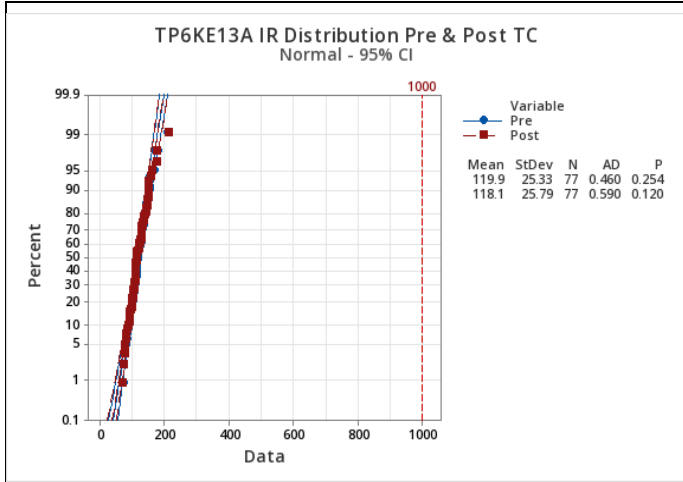
9.0 Recommendations & Conclusions:

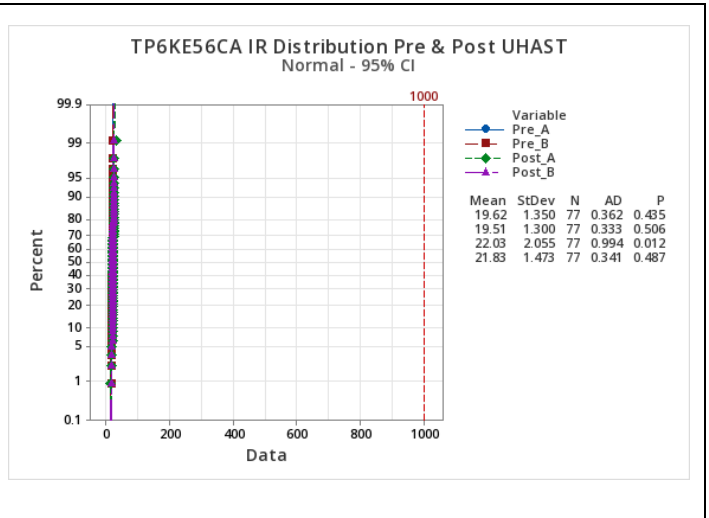
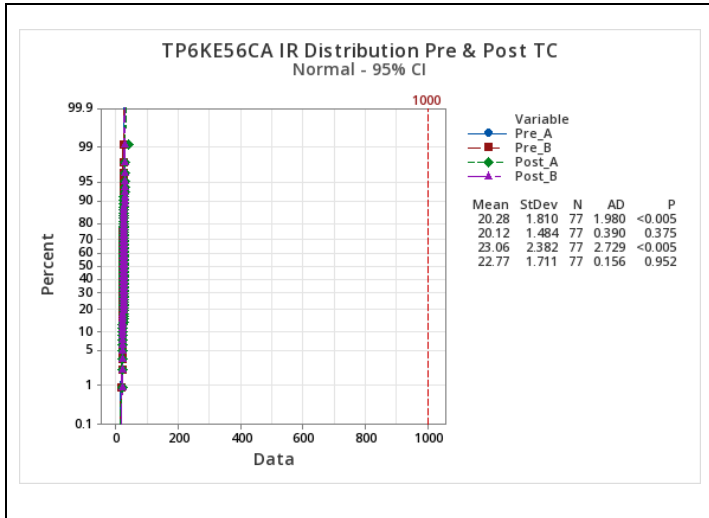
Based on the test results, it is determined that 1st Source site 2 is qualified and certified for production of above listed Littelfuse products.

10.0 Appendix A – Pre & Post Test Electrical Performance Distribution

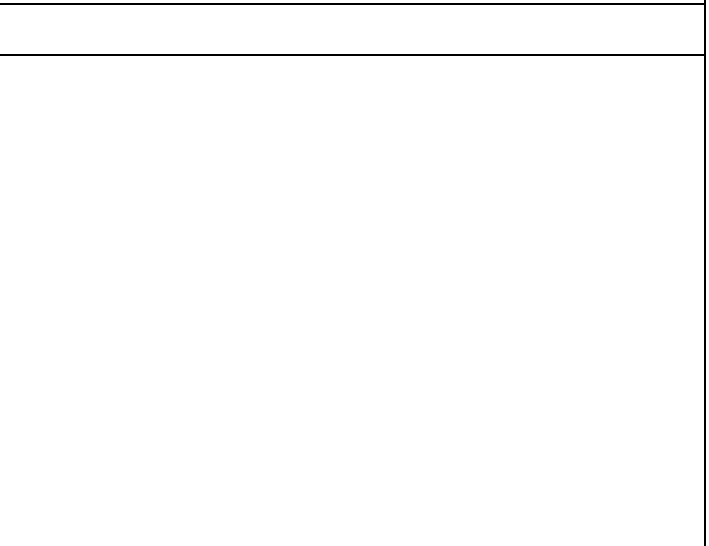
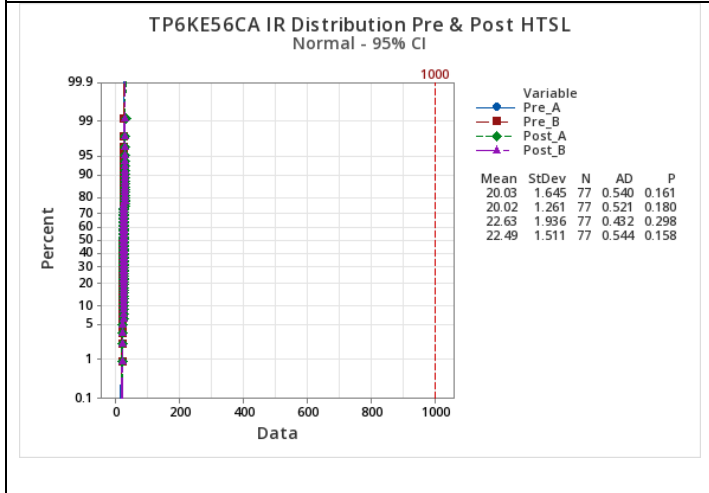
1st Source



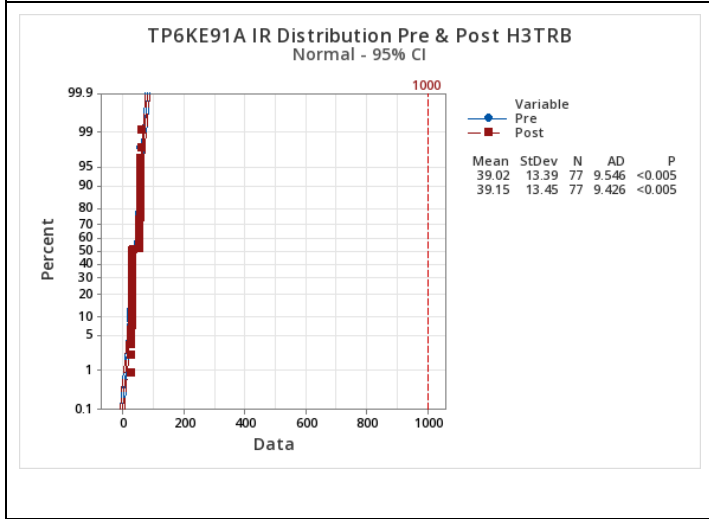




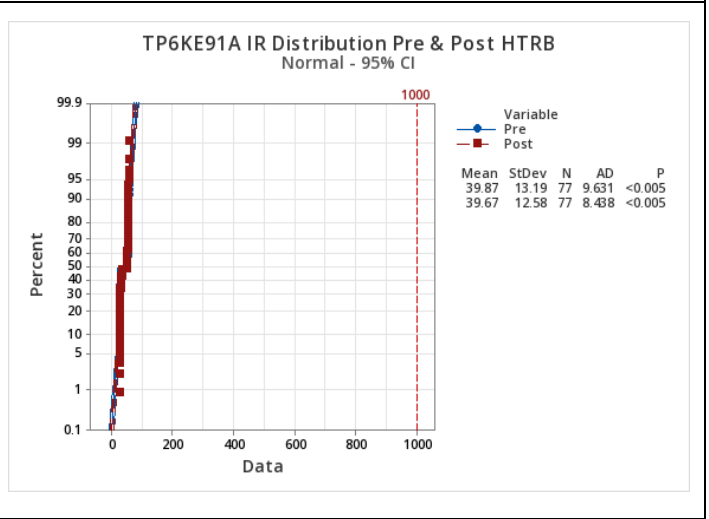
TP6KE56CA IR Distribution Pre & Post HTSL



TP6KE91A IR Distribution Pre & Post H3TRB

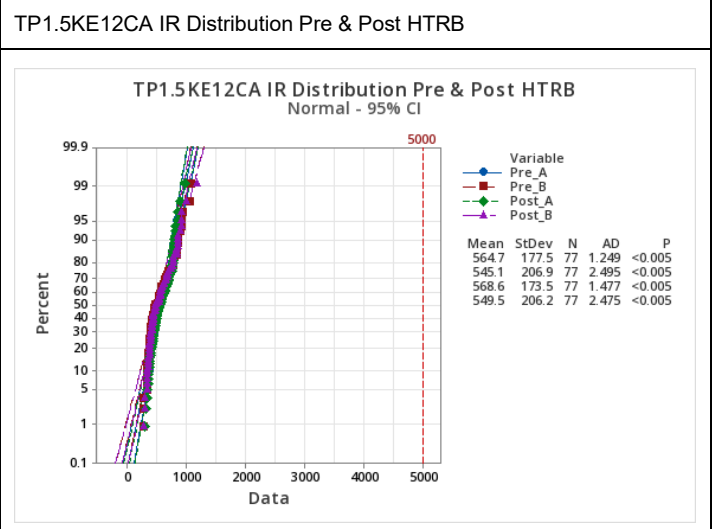
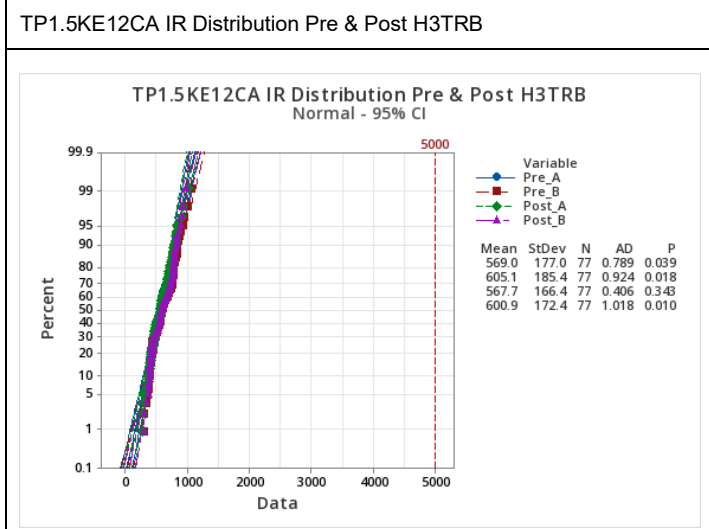
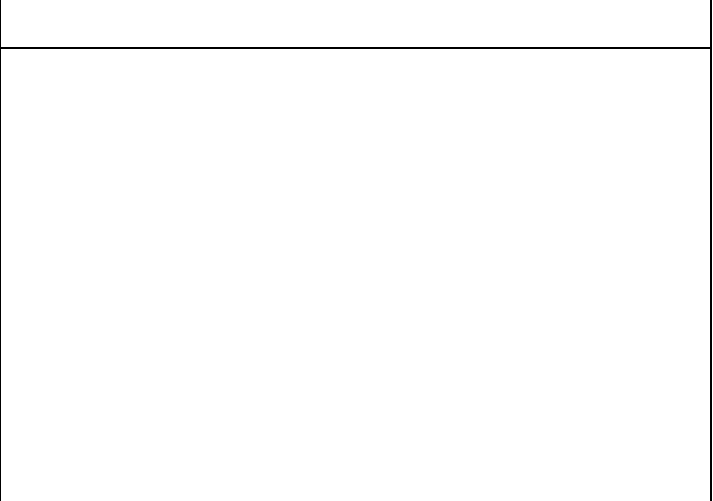
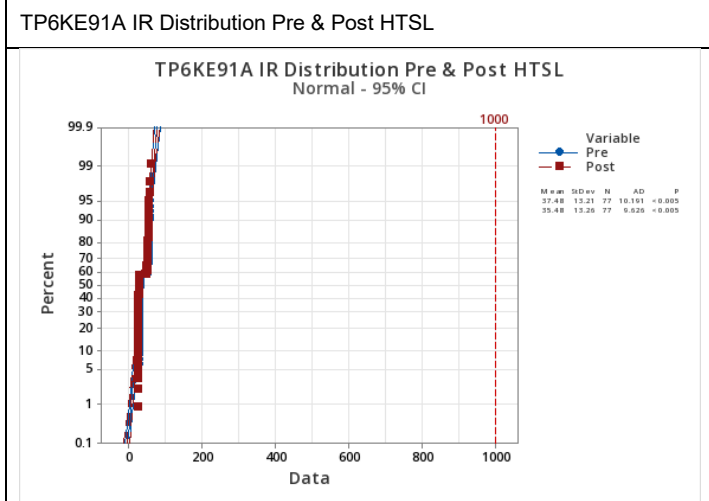
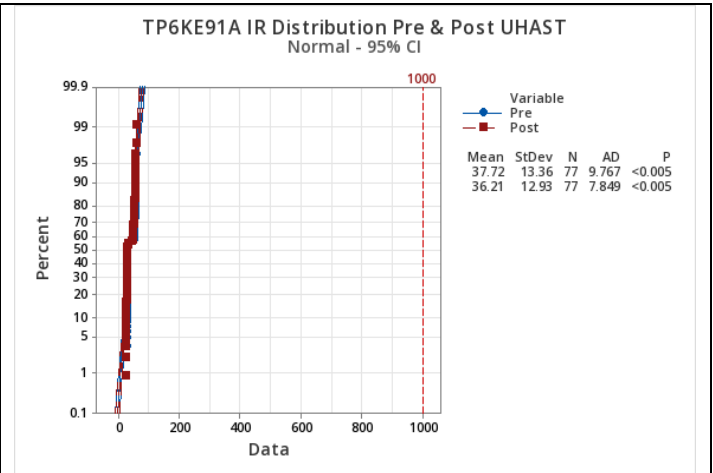
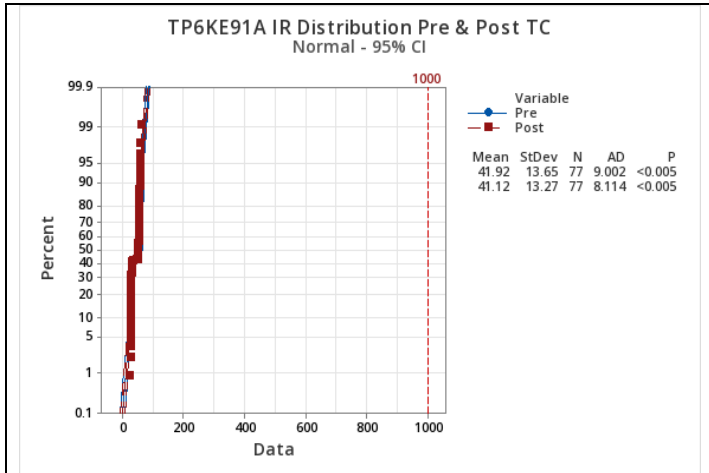


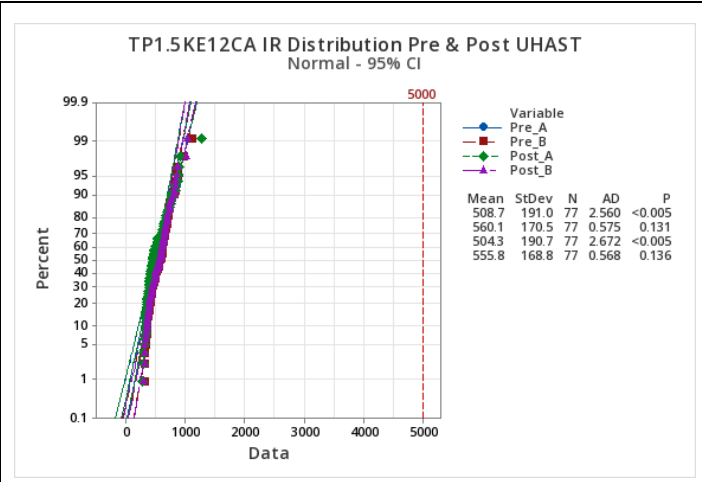
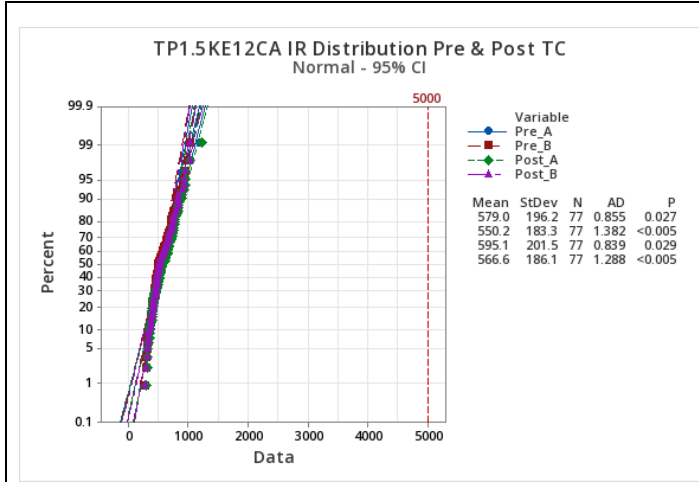
TP6KE91A IR Distribution Pre & Post HTRB



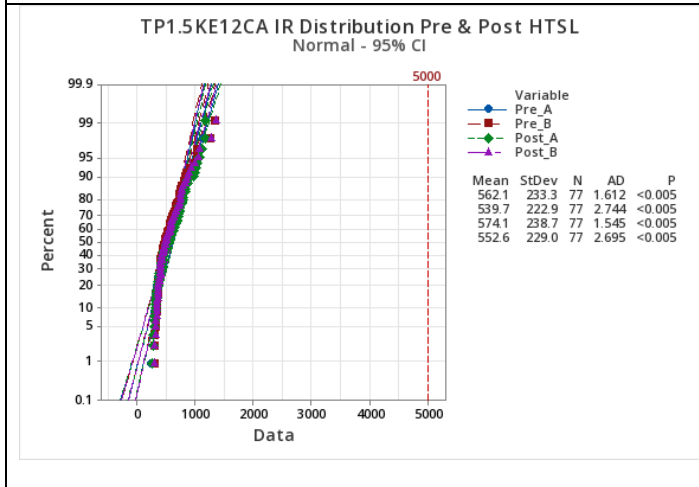
TP6KE91A IR Distribution Pre & Post TC

TP6KE91A IR Distribution Pre & Post UHAST





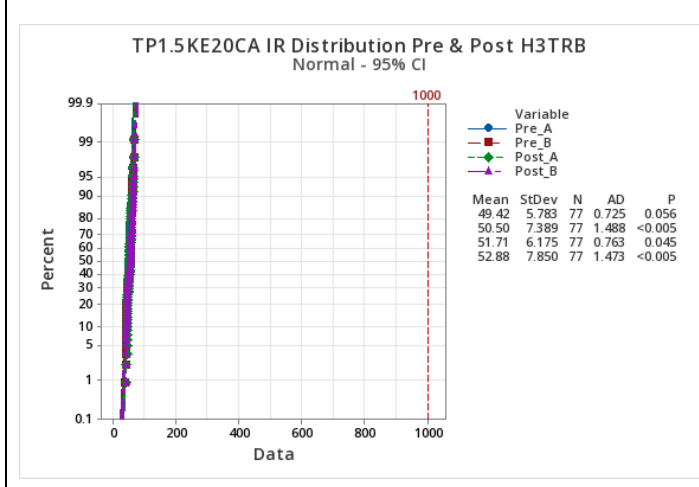
TP1.5KE12CA IR Distribution Pre & Post HTSL



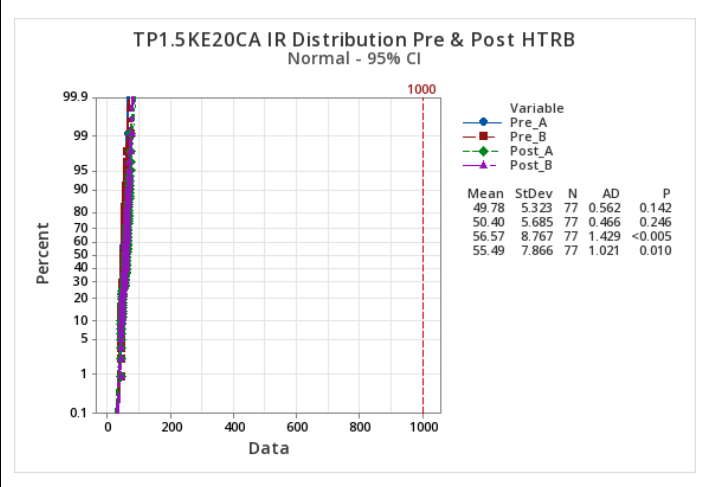
TP1.5KE20CA IR Distribution Pre & Post H3TRB



TP1.5KE20CA IR Distribution Pre & Post H3TRB

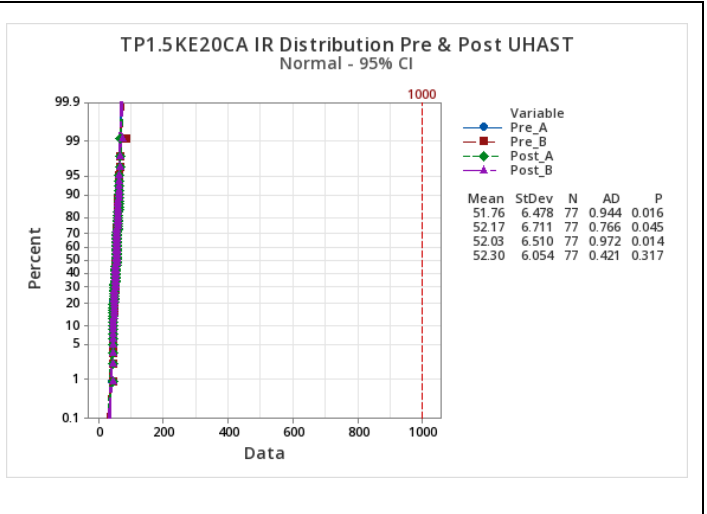
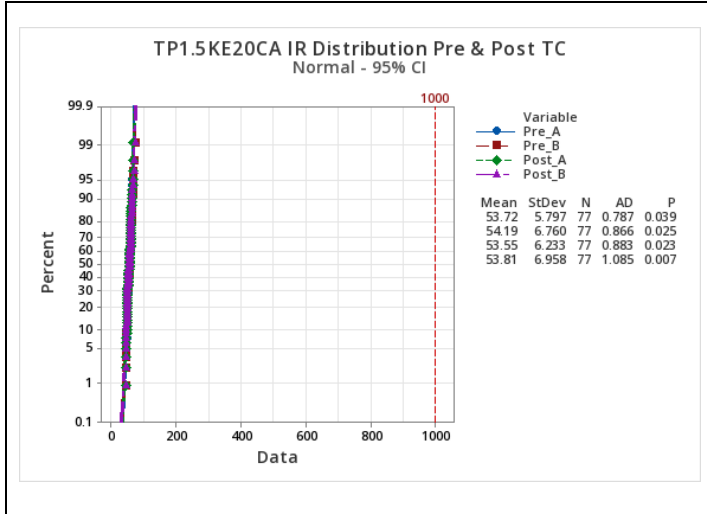


TP1.5KE20CA IR Distribution Pre & Post HTRB

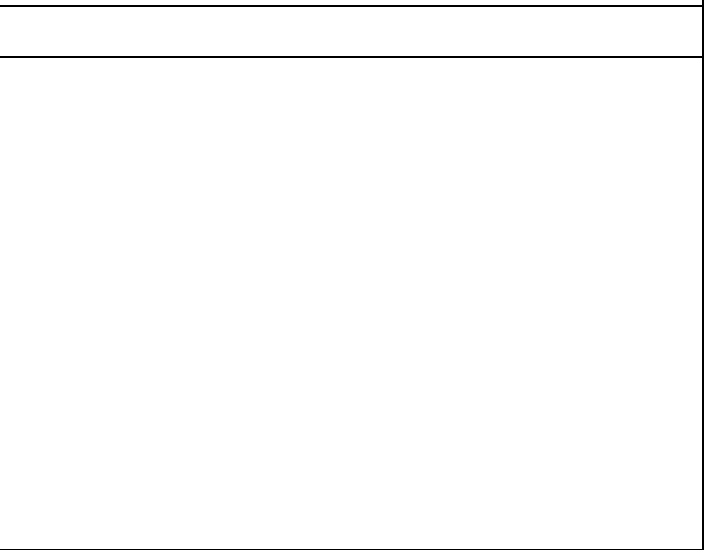
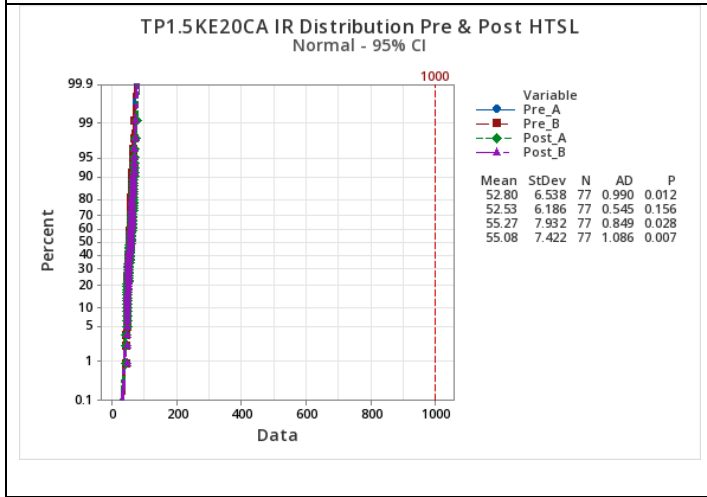


TP1.5KE20CA IR Distribution Pre & Post TC

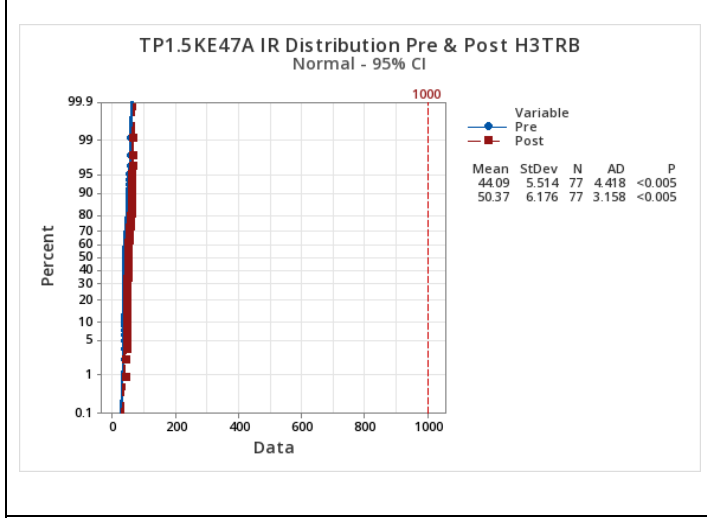
TP1.5KE20CA IR Distribution Pre & Post UHAST



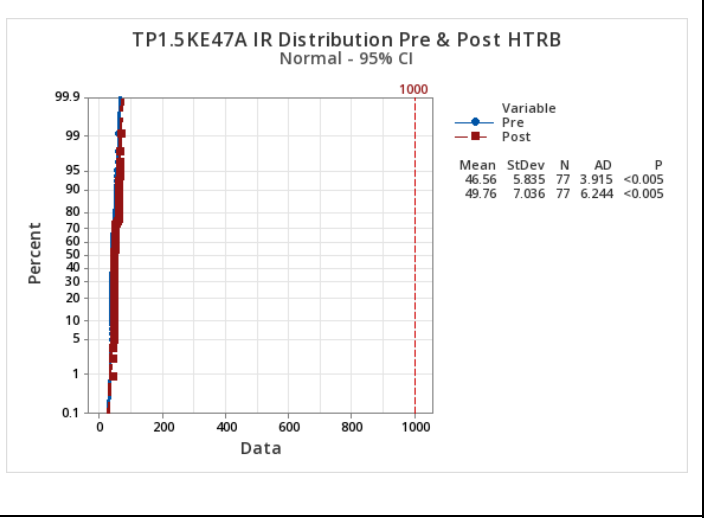
TP1.5KE20CA IR Distribution Pre & Post HTSL



TP1.5KE47A IR Distribution Pre & Post H3TRB

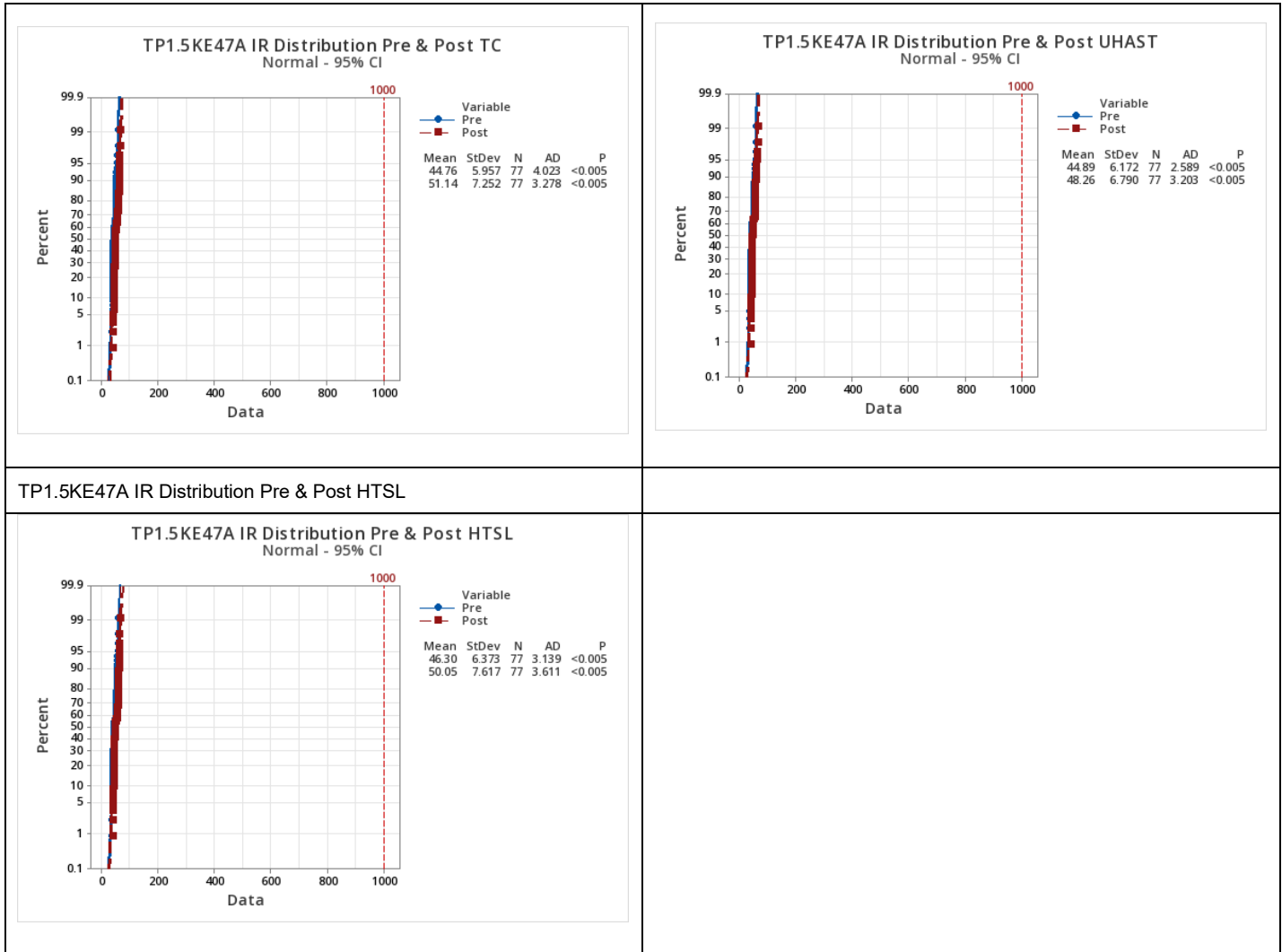


TP1.5KE47A IR Distribution Pre & Post HTRB



TP1.5KE47A IR Distribution Pre & Post TC

TP1.5KE47A IR Distribution Pre & Post UHAST



11.0 Approvals:

Yaling Fan
OSAT Operation Manager
Littelfuse, Wuxi

Lorna Zhang
OSAT PE Manager
Littelfuse, Wuxi

Package	Part Numbers
DO-15	TP6KE13A
DO-15	TP6KE13CA
DO-15	TP6KE15A
DO-15	TP6KE15CA
DO-15	TP6KE16A
DO-15	TP6KE16CA
DO-15	TP6KE18A
DO-15	TP6KE18CA
DO-15	TP6KE20A
DO-15	TP6KE20CA
DO-15	TP6KE22A
DO-15	TP6KE22CA
DO-15	TP6KE24A
DO-15	TP6KE24CA
DO-15	TP6KE27A
DO-15	TP6KE27CA
DO-15	TP6KE30A
DO-15	TP6KE30CA
DO-15	TP6KE33A
DO-15	TP6KE33CA
DO-15	TP6KE36A
DO-15	TP6KE36CA
DO-15	TP6KE39A
DO-15	TP6KE39CA
DO-15	TP6KE43A
DO-15	TP6KE43CA
DO-15	TP6KE47A
DO-15	TP6KE47CA
DO-15	TP6KE51A
DO-15	TP6KE51CA
DO-15	TP6KE56A
DO-15	TP6KE56CA
DO-15	TP6KE62A
DO-15	TP6KE62CA
DO-15	TP6KE68A
DO-15	TP6KE68CA
DO-15	TP6KE75A
DO-15	TP6KE75CA
DO-15	TP6KE82A
DO-15	TP6KE82CA
DO-15	TP6KE91A
DO-15	TP6KE91CA
DO-15	TP6KE62CA-B
DO-15	P6KE510CA-SU
DO-201	TP1.5KE12A
DO-201	TP1.5KE12CA
DO-201	TP1.5KE13A
DO-201	TP1.5KE13CA
DO-201	TP1.5KE15A

DO-201	TP1.5KE15CA
DO-201	TP1.5KE16A
DO-201	TP1.5KE16CA
DO-201	TP1.5KE18A
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DO-201	TP1.5KE22CA
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DO-201	TP1.5KE24CA
DO-201	TP1.5KE27A
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DO-201	TP1.5KE39CA
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DO-201	TP1.5KE43CA
DO-201	TP1.5KE47A
DO-201	TP1.5KE47CA